

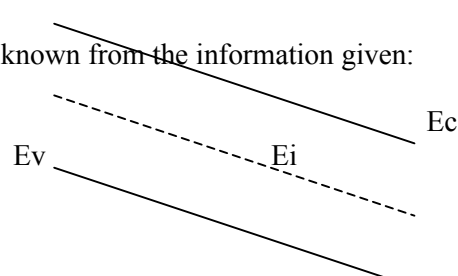


**First 25% Multiple Choice and True/False (Select the most correct answer)**

- 1.) (2-points) True or False: Drift current results from movement of electrons and holes from areas of high concentration to areas of low concentration.
- 2.) (2-points) True or False: Adding acceptors to a semiconductor results in more holes than electrons in the material.
- 3.) (2-points) True or False: If Carbon (Group 4 element) is used to dope InP (In is group 3, P is group 5), a p-type semiconductor will always result.
- 4.) (2-points) True or False: The energy band gap in a semiconductor is the energy required to free an electron that normally bonds atoms together, allowing the electron to move through the crystal.
- 5.) (2-points) True or False: When the fermi-energy is far above an allowed state, the state is probably occupied by an electron.

Select the **best** answer for 6-10:

- 6.) (3-points) Given Si and Ge are from group 4, In and Ga are from group 3 and P is from group 5, which of the following semiconductors is a binary compound semiconductor?
  - a.) Si
  - b.) Ge
  - c.)  $\text{In}_{0.47}\text{Ga}_{0.53}\text{P}$
  - d.) InP
- 7.) (3-points) The electron effective mass...
  - a.) ...is needed to account for the interaction of the electron with the periodic potentials in the crystal.
  - b.) ...is smaller than the mass of an electron in vacuum because the electron is moving at close to the speed of light.
  - c.) ...is always larger in compound semiconductor.
  - d.) ...is equal to the hole effective mass since they have equal but opposite charge.
- 8.) (3-points) The following energy band diagram indicates the material is:

a.) p-type	$E_c$	_____
<input checked="" type="radio"/> b.) n-type	$E_f$	_____
c.) intrinsic	$E_i$	-----
d.) s-type	$E_v$	_____
- 9.) (3-points) For to the following band diagram, what is known from the information given:
  - a.) The device is leaning on it's side.
  - b.) There is a non-zero electric field in this material
  - c.) There is no current flow in this device
  - d.) There is no electric field in this material.
- 10.) (3-points) A plane intersecting the coordinate axes at  $x=3a$ ,  $y=3a$  and  $z=3a$ , where  $a$  is the lattice constant has which of the following Miller indexes:
  - a.) (100)
  - b.) (111)
  - c.) (666)
  - d.) (333)
  - e.) Forget it, I will just quit school and go sell T-shirts at the beach.

**Second 25% Short Answer ("Plug and Chug"):**

- 11.) (5-points) A semiconductor with an intrinsic concentration,  $n_i = 1 \times 10^{14} \text{ cm}^{-3}$ , is doped with  $2 \times 10^{14} \text{ cm}^{-3}$  donors and  $1 \times 10^{11} \text{ cm}^{-3}$  acceptors. Assuming total ionization, what is the electron and hole concentrations?

$$n = \left( \frac{N_D - N_A}{2} \right) + \sqrt{\left( \frac{N_D - N_A}{2} \right)^2 + n_i^2}$$

$$n = \frac{2 \times 10^{14} - 1 \times 10^{11}}{2} + \sqrt{\left( \frac{2 \times 10^{14} - 1 \times 10^{11}}{2} \right)^2 + (1 \times 10^{14})^2}$$

$$n = 2.41 \times 10^{14} \text{ cm}^{-3}$$

$$p = \frac{n_i^2}{n} = \frac{(1 \times 10^{14})^2}{2.41 \times 10^{14}} = 4.14 \times 10^{13} \text{ cm}^{-3}$$

- 12.) (5-points) For the semiconductor in question 11, if the effective density of states in the conduction and valence band ( $N_c$  and  $N_v$ ) is  $N_c = 1 \times 10^{19}$  and  $N_v = 2 \times 10^{19} \text{ cm}^{-3}$ , what is the bandgap energy of the material at room temperature?

$$n_i = \sqrt{N_c N_v} e^{-E_g / 2kT}$$

$$1 \times 10^{14} \text{ cm}^{-3} = \sqrt{(1 \times 10^{19})(2 \times 10^{19})} e^{-E_g / [2(0.0259)]}$$

$$E_g = 0.614 \text{ eV}$$

- 13.) (5-points) For the material in questions 11 and 12, what is  $E_f - E_v$  (where  $E_f$  is the fermi energy and  $E_v$  is the top of the valence band)?

$$p = N_v e^{(E_v - E_f) / kT}$$

$$4.14 \times 10^{13} \text{ cm}^{-3} = 2 \times 10^{19} e^{-(E_f - E_v) / 0.0259}$$

$$E_f - E_v = 0.339 \text{ eV}$$

- 14.) (5-points) For the material in questions 11-13, the electron mobility is  $800 \text{ cm}^2/\text{Vsec}$  and the hole mobility is  $200 \text{ cm}^2/\text{Vsec}$ . What length of material is needed to make a resistor with resistance 1000 ohms using a cylinder with cross-sectional area  $0.001 \text{ cm}^2$ .

$$R = \frac{\rho L}{A}$$

$$\text{and } \rho = \frac{1}{q(\mu_n n + \mu_p p)}$$

$$\rho = \frac{1}{1.6e-19 (800(2.41e14) + 200(4.14e13))}$$

$$\rho = 31.08 \text{ } \Omega\text{-cm}$$

$$R = \frac{31.08 L}{0.001} = 1000 \text{ } \Omega$$

$$\boxed{L = 322 \text{ } \mu\text{m}} \text{ (or } 0.032 \text{ cm)}$$

- 15.) (5-points) A semiconductor has  $5e19 \text{ cm}^{-3}$  very deep acceptors (large binding energy) which are only partially ionized at room temperature and  $4e17 \text{ cm}^{-3}$  shallow donors (small binding energy). This results in  $5e17 \text{ cm}^{-3}$  holes,  $4e17 \text{ cm}^{-3}$  electrons and all the donors are ionized. How many unionized acceptors are present? (Hint: do not make this problem harder than it is)

All that is needed is the concept of Charge Neutrality!

$$p - N_A^- + N_d^+ - n = 0$$

$$5e17 - N_A^- + 4e17 - 4e17 = 0$$

$$N_A^- = 5e17 \text{ cm}^{-3}$$

⇓

Unionized Acceptors,  $N_A^0 = N_A - N_A^-$

$$N_A^0 = 5e19 - 5e17$$

$$\boxed{N_A^0 = 4.95e19 \text{ cm}^{-3}}$$

**Third 25% Problems (3<sup>rd</sup> 25%)**

16.) (25-points)

A semiconductor has the following parameters:

Mobility,  $\mu_p = 200 \text{ cm}^2/\text{VSec}$

Substrate relative Dielectric Constant,  $\epsilon_{r\text{-semiconductor}} = K_S = 11.7$

Dielectric Constant of free space,  $\epsilon_0 = 8.854 \times 10^{-14} \text{ F/cm}$

Substrate intrinsic concentration,  $n_i = 1 \times 10^{10} \text{ cm}^{-3}$

Substrate Doping,  $N_A(x) = 1 \times 10^{15} e^{4.6 \sin(2\pi x/100 \mu\text{m})} \text{ cm}^{-3}$

Plot and label (label the maximum and minimum values) the electric field from  $x=0$  to  $x=100 \mu\text{m}$  for this material in equilibrium.

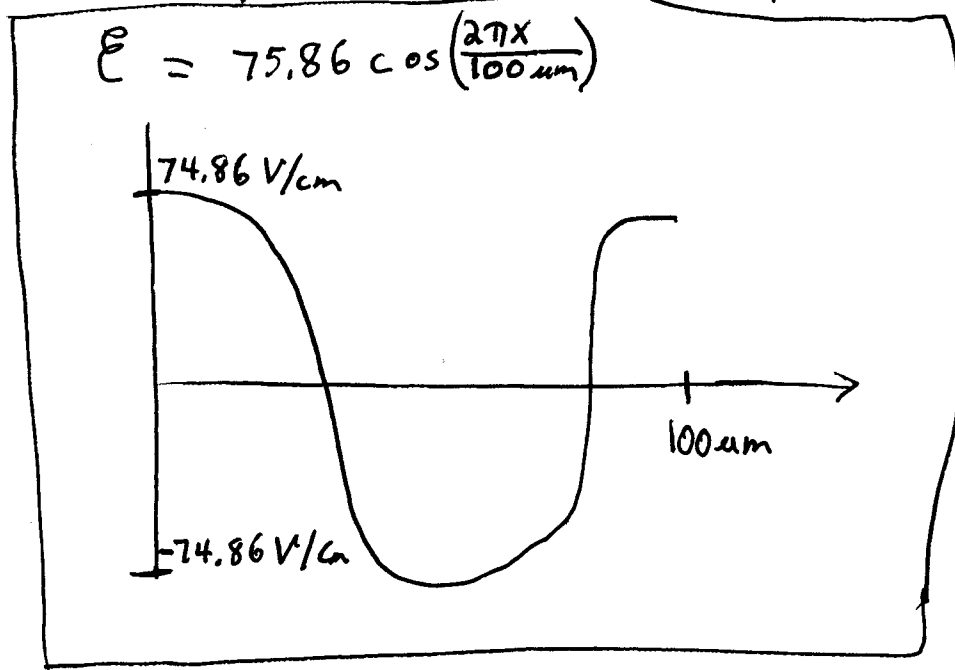
Two ways to solve this.

Method 1: Almost exactly like our homework problem!

$$\begin{aligned} E_f - E_i &= -kT \ln\left(\frac{N_A(x)}{n_i}\right) \\ &= -kT \ln[N_A(x)] + kT \ln(n_i) \\ &= -kT \left[ \ln(1 \times 10^{15}) + \ln\left(e^{4.6 \sin(2\pi x/100 \mu\text{m})}\right) \right] + kT \ln(n_i) \end{aligned}$$

$$E_i = E_f + kT \left[ \ln(1 \times 10^{15}) + 4.6 \sin(2\pi x/100 \mu\text{m}) \right] - kT \ln(n_i)$$

$$\mathcal{E} = \frac{1}{q} \frac{dE_i}{dx} = \frac{kT}{q} \left( \frac{2\pi}{100 \mu\text{m}} \right) 4.6 \cos\left(\frac{2\pi x}{100 \mu\text{m}}\right)$$



Method 2: In equilibrium,  $\bar{J}_p = \bar{J}_n = 0$ .

$$\Rightarrow \bar{J}_p = \underbrace{q \mu_p p E}_{\text{Drift}} - \underbrace{q D_p \nabla p}_{\text{Diffusion}} = 0$$

$$E = \frac{q D_p \nabla p}{q \mu_p p} = \frac{kT}{q} \frac{\nabla p}{p}$$

Einstein Relationship:  $\frac{kT}{q} = \frac{D_p}{\mu_p}$

$$E = \frac{kT}{q} \left[ \frac{1e15 e^{4.6 \sin(2\pi x/100 \mu\text{m})} \left[ 4.6 \left( \frac{2\pi}{100 \mu\text{m}} \right) \cos \frac{2\pi x}{100 \mu\text{m}} \right]}{1e15 e^{4.6 \sin(2\pi x/100 \mu\text{m})}} \right]$$

$$E = \left( \frac{kT}{q} \right) 4.6 \left( \frac{2\pi}{100 \mu\text{m}} \right) \cos \left( \frac{2\pi x}{100 \mu\text{m}} \right)$$

Same plot as before....

Also, significant points given for a well reasoned qualitative (no #s) answer arrived at by:

$N_A(x) \Rightarrow$  Equilibrium Band diagram  $\Rightarrow$  electrostatic potential  $\Rightarrow$  Electric Field

Pulling all the concepts together for a useful purpose: (4<sup>th</sup> 25%)

17.) (25-points)

Light from two identical light sources is absorbed on BOTH sides of a silicon wafer of thickness 520  $\mu\text{m}$  (the wafer is similar to that passed around in class). The wafer is p-type and is uniformly doped with  $10^{17} \text{ cm}^{-3}$

Steady State

$$\frac{d\Delta n_p}{dx} = 0$$

$$\frac{d^2 \Delta n_p}{dx^2} = 0$$

$G_L$  holes

$G_L$  electrons

$$10^{17} \text{ cm}^{-3}/\text{sec}$$

acceptors. The light has been on since the dinosaurs walked the earth (a very long time!) and

can be approximated as being absorbed uniformly within a 10  $\mu\text{m}$  region

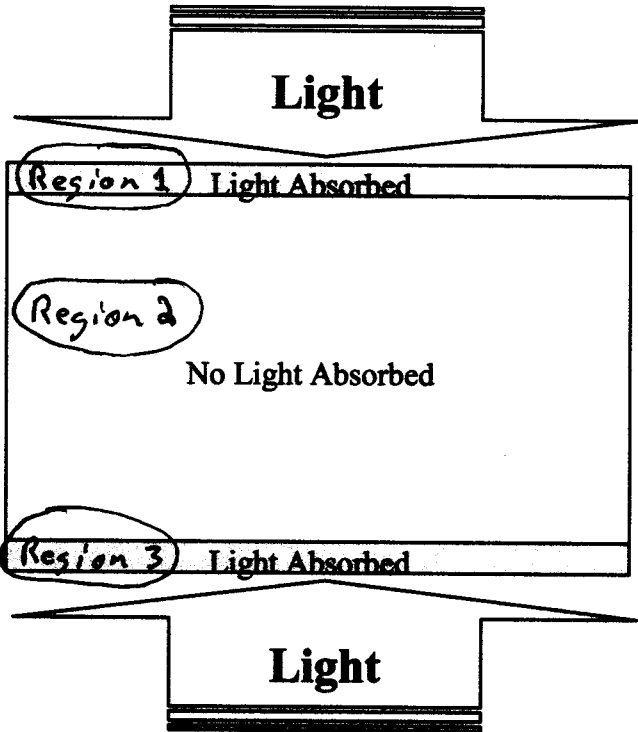
near either surface (i.e. no light penetrates past 10  $\mu\text{m}$  into the wafer). The diffusion coefficient for electrons is  $2.5 \text{ cm}^2/\text{Sec.} = D_n$

If the excess HOLE generation rate is  $10^{17} \text{ cm}^{-3}/\text{sec}$  and the minority carrier lifetime is 1 millisecond ( $1 \times 10^{-3}$  seconds);

What is the excess electron concentration for all positions in the wafer. Hint: break the problem up into three regions (two of which have identical solutions) and use the x axis pictured above. Your answer should be a numeric expression with x being the only independent variable.

(Bonus-10 points) The excess electron concentration changes with position in the wafer. Thus, an electron current density must result. What is the magnitude and direction of this current density at  $x=125 \mu\text{m}$  from the top surface?

(Bonus-5 points) Explain why no net current would flow.



Given:  $0 = D_n \frac{d^2 \Delta n_p}{dx^2} - \frac{\Delta n_p}{\tau_n}$

General Solution is:  $\Delta n_p(x) = Ae^{-x/L_n} + Be^{+x/L_n}$

Given:  $0 = D_n \frac{d^2 \Delta n_p}{dx^2} - \frac{\Delta n_p}{\tau_n} + G_L$

General Solution is:  $\Delta n_p(x) = Ae^{-x/L_n} + Be^{+x/L_n} + G_L \tau_n$

Given:  $0 = D_n \frac{d^2 \Delta n_p}{dx^2}$

General Solution is:  $\Delta n_p(x) = A + Bx$

Given:  $0 = D_n \frac{d^2 \Delta n_p}{dx^2} + G_L$

General Solution is:  $\Delta n_p(x) = Ax^2 + Bx + C$

Given:  $\frac{d\Delta n_p}{dt} = -\frac{\Delta n_p}{\tau_n}$

General Solution is:  $\Delta n_p(t) = \Delta n_p(t=0)e^{-t/\tau_n}$

Given:  $0 = -\frac{\Delta n_p}{\tau_n} + G_L$

General Solution is:  $\Delta n_p = G_L \tau_n$

Extra work can be done here, but clearly indicate with problem you are solving.

$$\frac{d\Delta n_p}{dx} = D_n \frac{d^2 \Delta n_p}{dx^2} - \frac{\Delta n_p}{\tau_n} + G_L$$

For  $-10 \mu\text{m} < x < 0$  and  $500 < x < 510 \mu\text{m}$ :

$$0 = -\frac{\Delta n_p}{\tau_n} + G_L$$

$$\begin{aligned} \Delta n_p &= G_L \tau_n \\ &= \frac{10^{17} \text{ cm}^{-3}}{\text{sec}} (1e-3 \text{ sec}) \end{aligned}$$

$$(*) \quad \boxed{\Delta n_p = 1e14 \text{ cm}^{-3}}$$

For  $0 < x < 500$ :

$$0 = D_n \frac{d^2 \Delta n_p}{dx^2} - \frac{\Delta n_p}{\tau_n}$$

$$\Delta n_p(x) = A e^{-x/L_n} + B e^{+x/L_n}$$

$$\text{where } L_n = \sqrt{D_n \tau_n}$$

$$= \sqrt{(2.5 \text{ cm}^2/\text{sec})(1e-3 \text{ sec})}$$

$$= 0.05 \text{ cm} = 500 \mu\text{m}$$

Boundary Conditions:

$$\Delta n_p(x=0) = A + B = 1e14 \text{ cm}^{-3} \quad (\text{from } (*))$$

$$B = 1e14 - A$$

$$\Delta n_p(x=500 \mu\text{m}) = A e^{-500/500} + B e^{+500/500} = 1e14$$

$$= A e^{-1} + B e^1$$

$$= A e^{-1} + (1e14 - A) e^1$$



Extra work can be done here, but clearly indicate with problem you are solving.

$$A[e^{-1} - e^1] = 1e14 - 1e14e^1$$

$$A = \frac{-1.72e14}{2.35} = 7.31e13 \text{ cm}^{-3}$$

$$B = 2.69e13 \text{ cm}^{-3}$$

$$\Delta n_p(x) = \begin{cases} 1e14 \text{ cm}^{-3} \\ 7.31e13 e^{-x/500 \mu\text{m}} + 2.69e13 e^{x/500 \mu\text{m}} \\ 1e14 \text{ cm}^{-3} \end{cases}$$

Bonus #1:  $J_n = q \cancel{\mu_n n_p E} + q D_n \frac{dn_p}{dx}$   $\rightarrow 0$  due to no electric field  $\rightarrow n_p = n_{op} + \Delta n_p$

$$\Rightarrow J_n = +q D_n \frac{d\Delta n_p}{dx}$$

$$\frac{dn_p}{dx} = \frac{dn_{op}}{dx} + \frac{d\Delta n_p}{dx}$$

$$= +q D_n \left[ \frac{-7.31e13 \text{ cm}^{-3}}{0.05 \text{ cm}} e^{-x/500 \mu\text{m}} + \frac{2.69e13 \text{ cm}^{-3}}{0.05} e^{x/500 \mu\text{m}} \right]$$

$$J_n(x) = -0.000585 e^{-x/500 \mu\text{m}} + 0.000215 e^{x/500 \mu\text{m}}$$

$$J_n(x=125 \mu\text{m}) = -180 \mu\text{A}/\text{cm}^2$$

Direction is toward the upper surface

Extra work can be done here, but clearly indicate with problem you are solving.

Bonus #2: The only reason why a net current is not flowing is that the light is symmetrically applied to the wafer. Thus,  $\bar{e}$  current flows from the center toward the edges and hole current flows from the edges toward the center.

Note: Unless  $\mu_p = \mu_n$ , ~~the net~~

$$J_n(x=x') \neq J_p(x=x').$$

$$(If \mu_p = \mu_n \quad J_n = J_p).$$

# Histogram of Test Scores

